

Notice of References Cited	Application/Control No. 10/045,571	Applicant(s)/Patent Under Reexamination GARDNER ET AL.	
	Examiner VanThu Nguyen	Art Unit 2824	Page 1 of 1

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	B	US-5,007,026	04-1991	Gaultier et al.	365/185.04
	C	US-4,939,694	07-1990	Eaton et al.	365/200
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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